Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
09/749,482	LEE, BYOUNG-JOON	
Examiner	Art Unit	
Andrew Lee	2663	

Andrew Lee

Subclass	Dete	
	Date	Examiner
238,254	1/6/2006	AL
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	238,254	238,254 1/6/2006

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			-	

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
Inventor search and interference Search East	1/6/2006	AL